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S. Carmignato, W. Dewulf, R. Leach (Eds.)

Industrial X-Ray Computed Tomography

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Simone Carmignato is Associate Professor of Manufacturing Engineering and Manufacturing Metrology at the University of Padua, Italy. His research activities are in the area of precision engineering and dimensional metrology, with focus on industrial tomography and advanced coordinate metrology. In 2012, he was awarded the F. W. Taylor Medal from CIRP, the International Academy of Production Engineering.

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Richard Leach is Chair in Metrology at The University of Nottingham, UK, and heads up the Manufacturing Metrology Team. Richard's current interests are the dimensional measurement of precision and additive manufactured structures. His research themes include the measurement of surface topography, development of methods for measuring 3D structures, development of methods for controlling large surfaces to high resolution in industrial applications and X-ray computed tomography.



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